Application Number Docket Number (Optional) 10/601,496 16772 TION DISCLOSURE CITATION Applicant(s) Takeshi Ozawa, et al. (Use several sheets if necessary) Filing Date Group Art Unit June 23, 2003 Unassigned **U.S. PATENT DOCUMENTS** EXÂMINER FILING DATE DATE NAME CLASS SUBCLASS REF DOCUMENT NUMBER INITIAL IF APPROPRIATE FOREIGN PATENT DOCUMENTS Translation SUBCLASS **CLASS** DOCUMENT NUMBER DATE COUNTRY /AL/ EP 1 256 310 A2 11/13/2002 **EPO** OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) U.S. Patent Application Publication No. US 2002/0062061 A1, pub; ished May 23, 2002, issued to Kaneko et al.

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/Alex Kok Liew/ (04/01/2007)

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